

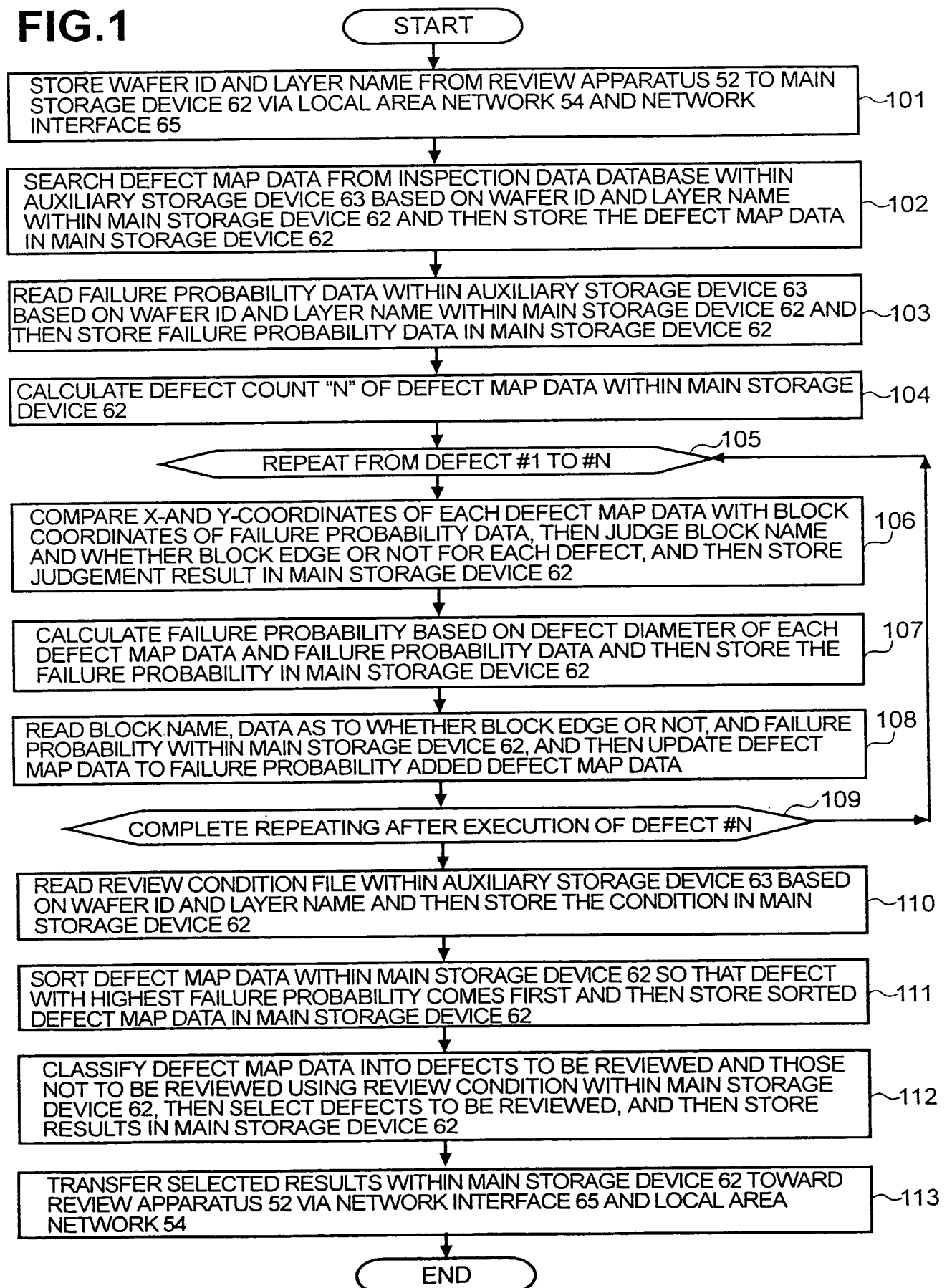
Applicant: Makoto Ono, et al.

Title: Inspection System and Semiconductor Device Manufacturing...

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FIG.1



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FIG. 2

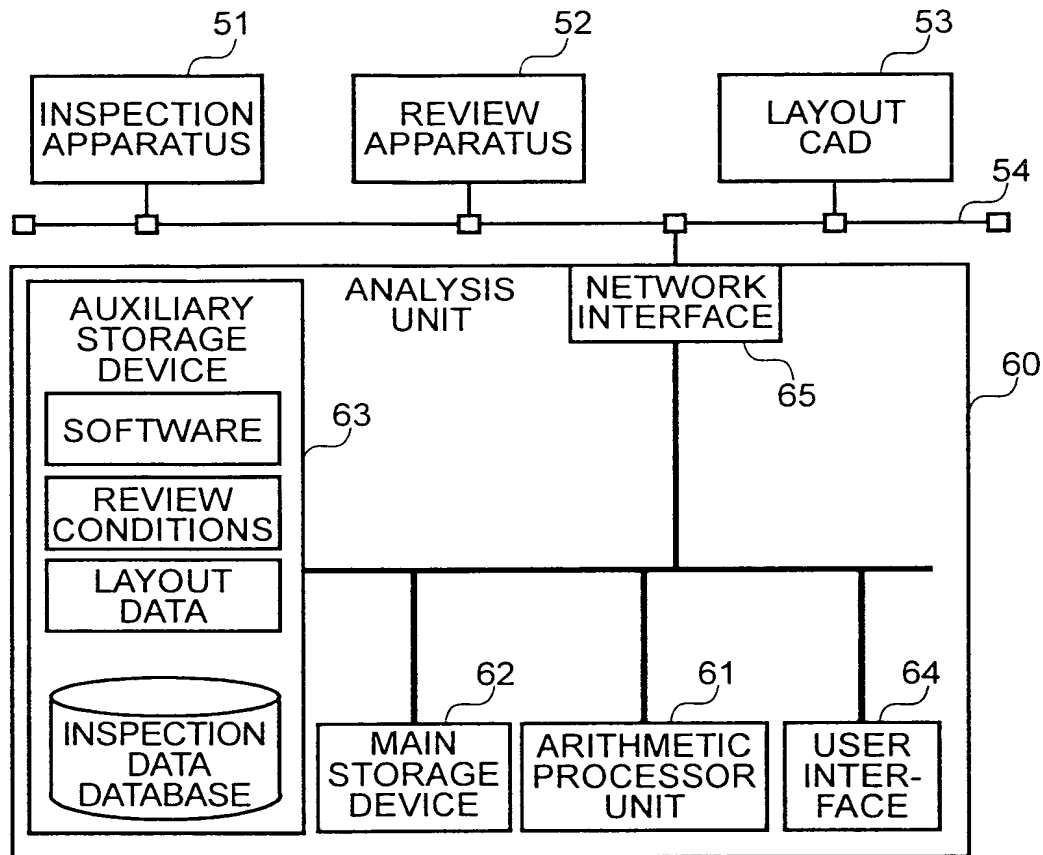


FIG. 3

CHIP NO.,	CHIP COLUMN,	CHIP ROW,	X,	Y,	DEFECT DIAMETER
1,	1,	1,	73,	67,	2.4
2,	5,	1,	25,	89,	0.3
3,	4,	2,	47,	69,	1.5
4,	5,	3,	80,	82,	1.0
5,	6,	5,	52,	78,	1.2
6,	3,	5,	71,	32,	0.2
7,	3,	7,	87,	90,	0.7
8,	2,	6,	77,	38,	0.3
9,	0,	4,	83,	45,	0.8
10,	2,	3,	49,	9,	1.9

FIG.4

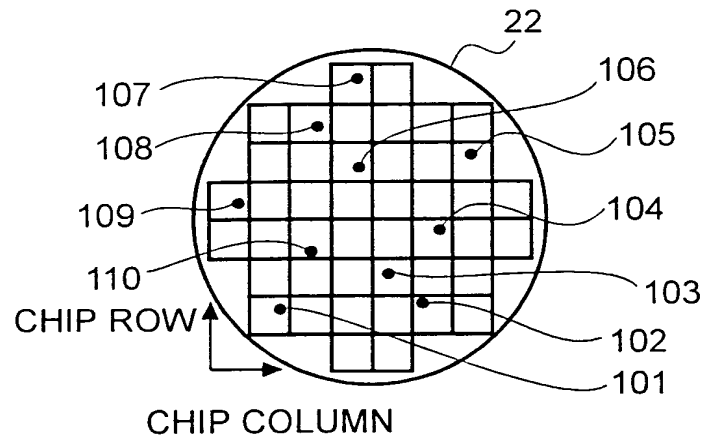
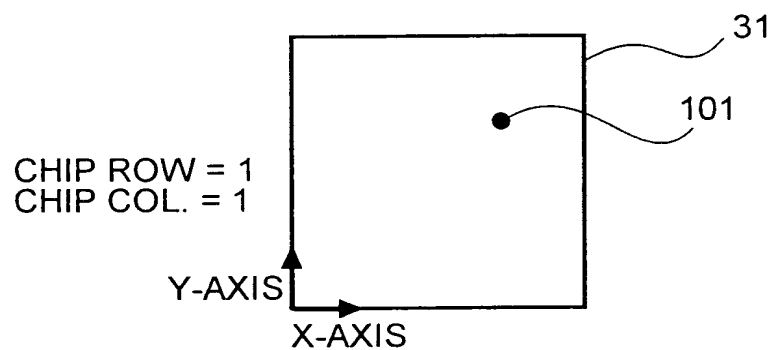


FIG.5



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FIG.6

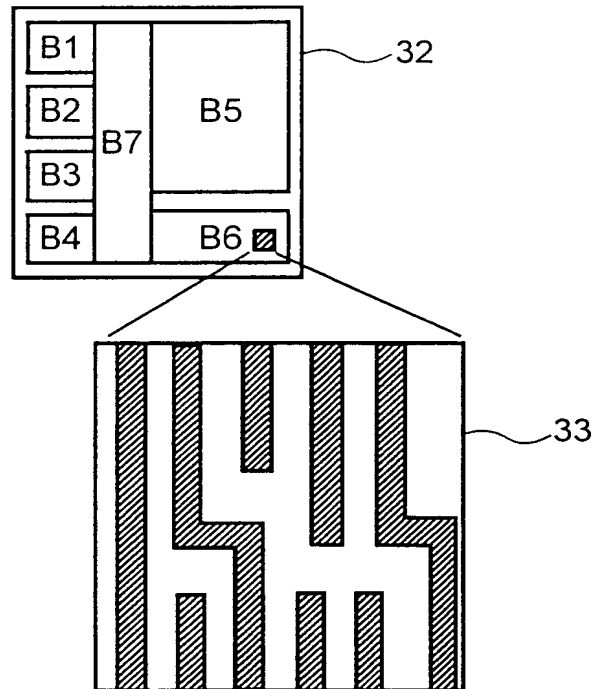


FIG.7

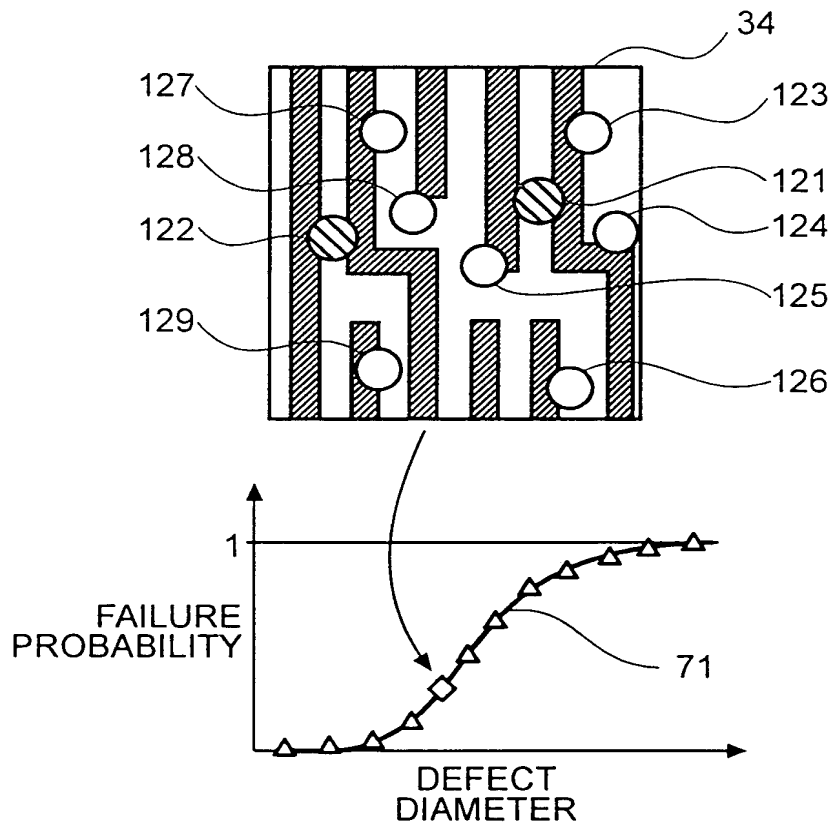
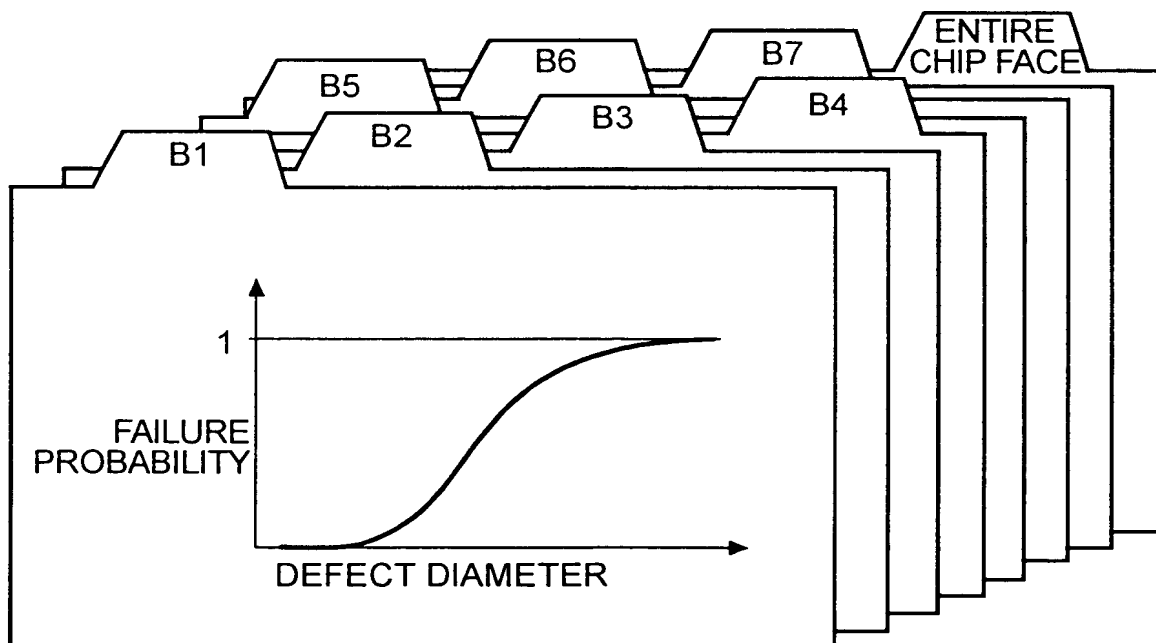


FIG.8



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Title: Defect Detection System and Semiconductor Device Manufacturing...

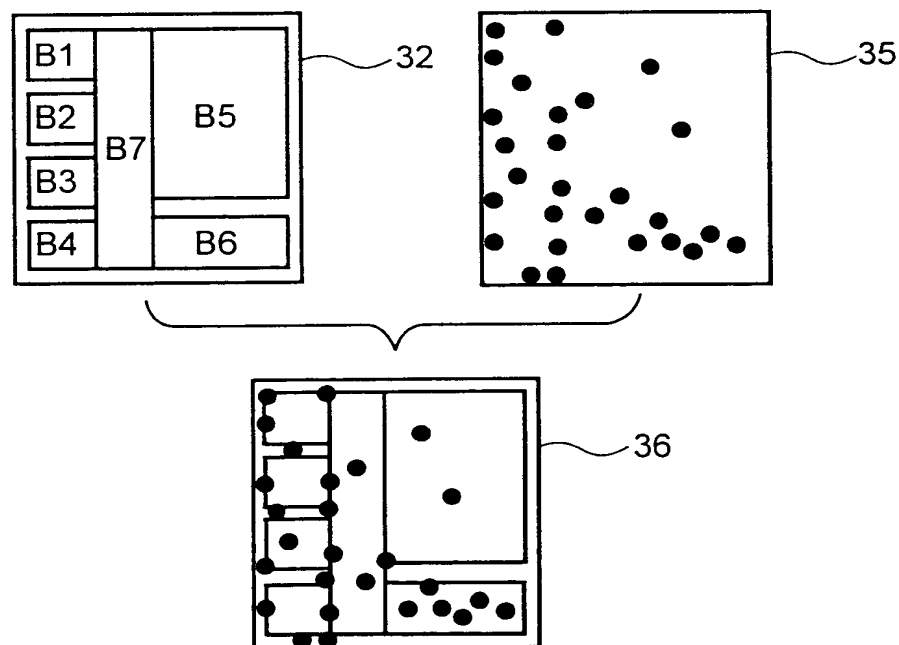
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FIG. 9

PRODUCT TYPE NAME	
LOGIC234	
LAYER NAME	
METAL1	
BLOCK NAME	
B1	
BLOCK COORDINATES	
RECTANGLE DIAGONAL	
ANGLE (5, 80) - (20, 95)	
DEFECT	FAILURE
DIAMETER	PROBABILITY
0.05,	0.00
0.10,	0.01
0.15,	0.02
0.20,	0.03
0.25,	0.05
.	.
.	.
9.95,	1.00
10.00,	1.00

FIG. 10



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FIG.11

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NO.,	CHIP COL.,	CHIP ROW,	X,	Y,	SIZE,	BLOCK,	BLOCK EDGE,	FAILURE PROBABILITY
1,	1,	1,	73,	67,	2.4,	B5,	no,	0.83
2,	5,	1,	25,	89,	0.3,	B1,	no,	0.07
3,	4,	2,	47,	69,	1.5,	B2,	no,	0.26
4,	5,	3,	80,	82,	1.0,	B5,	no,	0.38
5,	6,	5,	52,	78,	1.2,	B5,	yes,	0.50
6,	3,	5,	71,	32,	0.2,	B6,	yes,	0.05
7,	3,	7,	87,	90,	0.7,	B5,	no,	0.35
8,	2,	6,	77,	38,	0.3,	B6,	no,	0.07
9,	0,	4,	83,	45,	0.8,	B5,	no,	0.28
10,	2,	3,	49,	9,	1.9,	B7,	no,	0.06

FIG.12

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NO.,	CHIP COL.,	CHIP ROW,	X,	Y,	SIZE,	BLOCK,	BLOCK EDGE,	FAILURE PROBABILITY
1,	1,	1,	73,	67,	2.4,	B5,	no,	0.83
5,	6,	5,	52,	78,	1.2,	B5,	yes,	0.50
4,	5,	3,	80,	82,	1.0,	B5,	no,	0.38
7,	3,	7,	87,	90,	0.7,	B5,	no,	0.35
9,	0,	4,	83,	45,	0.8,	B5,	no,	0.28
3,	4,	2,	47,	69,	1.5,	B2,	no,	0.26
8,	2,	6,	77,	38,	0.3,	B6,	no,	0.07
2,	5,	1,	25,	89,	0.3,	B1,	no,	0.07
10,	2,	3,	49,	9,	1.9,	B7,	no,	0.06
6,	3,	5,	71,	32,	0.2,	B6,	yes,	0.05

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FIG.13

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NO.,	CHIP COL.,	CHIP ROW,	X,	Y,	SIZE,	BLOCK,	BLOCK EDGE,	FAILURE PROBABILITY
1,	1,	1,	73,	67,	2.4,	B5,	no,	0.83
4,	5,	3,	80,	82,	1.0,	B5,	no,	0.38
7,	3,	7,	87,	90,	0.7,	B5,	no,	0.35
9,	0,	4,	83,	45,	0.8,	B5,	no,	0.28
3,	4,	2,	47,	69,	1.5,	B2,	no,	0.26

FIG.14

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NO.,	CHIP COL.,	CHIP ROW,	X,	Y,	SIZE,	BLOCK,	BLOCK EDGE,	FAILURE PROBABILITY
3,	4,	2,	47,	69,	1.5,	B2,	no,	0.26
8,	2,	6,	77,	38,	0.3,	B6,	no,	0.07
2,	5,	1,	25,	89,	0.3,	B1,	no,	0.07
10,	2,	3,	49,	9,	1.9,	B7,	no,	0.06
6,	3,	5,	71,	32,	0.2,	B6,	yes,	0.05

FIG.15

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NO.,	CHIP COL.,	CHIP ROW,	X,	Y,	SIZE,	BLOCK,	BLOCK EDGE,	FAILURE PROBABILITY
1,	1,	1,	73,	67,	2.4,	B5,	no,	0.83
5,	6,	5,	52,	78,	1.2,	B5,	yes,	0.50
4,	5,	3,	80,	82,	1.0,	B5,	no,	0.38
7,	3,	7,	87,	90,	0.7,	B5,	no,	0.35
9,	0,	4,	83,	45,	0.8,	B5,	no,	0.28

FIG.16

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PRODUCT TYPE NAME
LOGIC234
LAYER NAME
METAL1
MAXIMUM DEFECT NUMBER
20
OBJECT
FAILURE PROBABILITY
0.30 OR GREATER
EXCLUDED
B5
BLOCK EDGES B1, B2

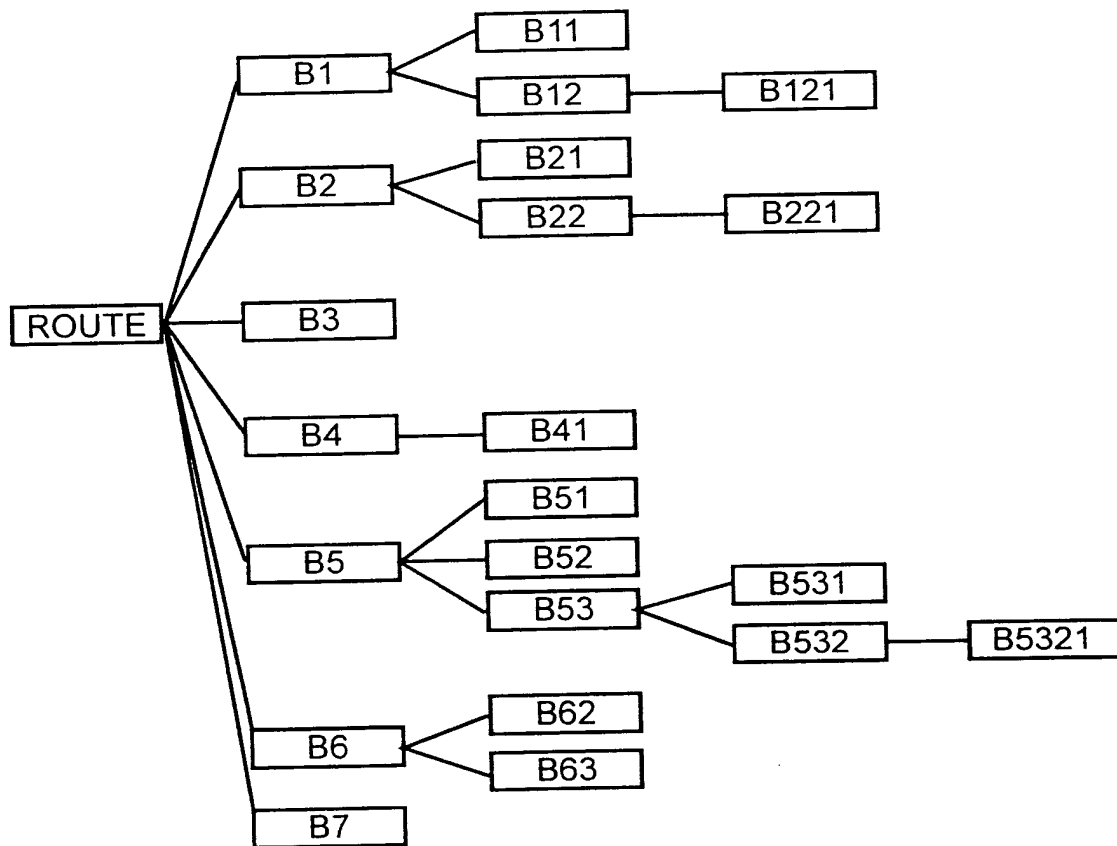
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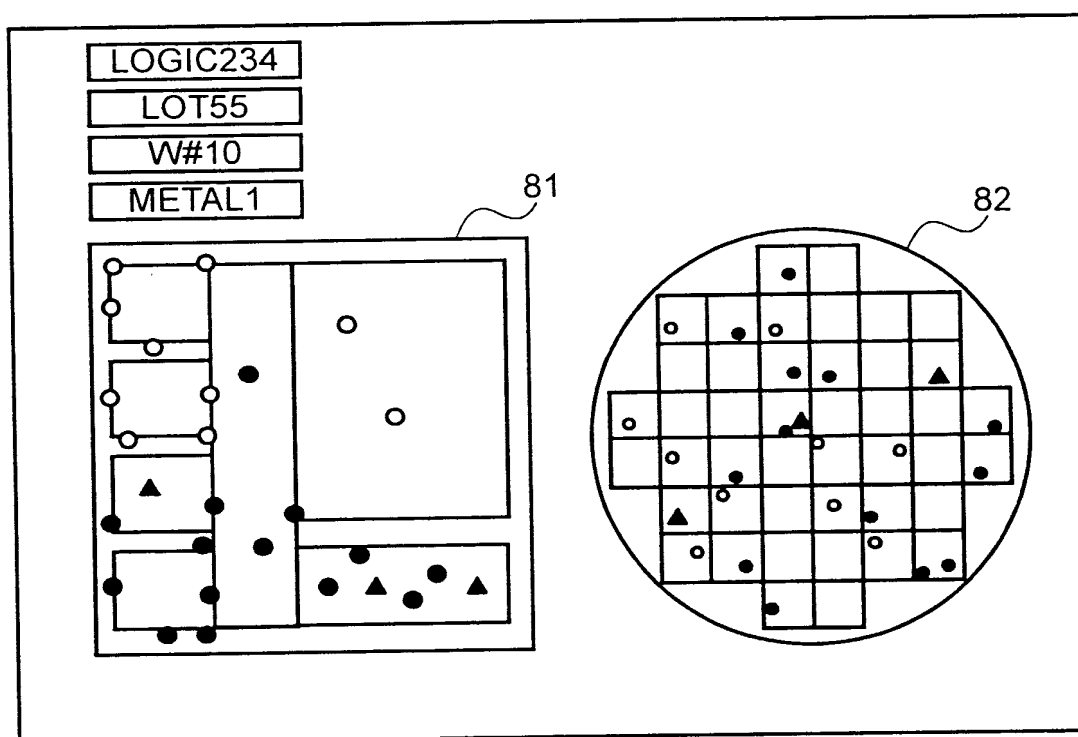
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FIG.17



TOP SECRET

FIG.18



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FIG. 19

